

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/581,593	MIYOSHI ET AL.		
Examiner	Art Unit		

1725

Len Tran

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SEARCHED							
Class	Subclass	Date	Examiner				
422	139	12/1/2004	LT				
	141						
	142						
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
422	all above	12/1/2004	LT	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
East and Palm		12/1/2004	LT		
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